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# Mapping HCPV Module or System Response to Solar Incident Angle

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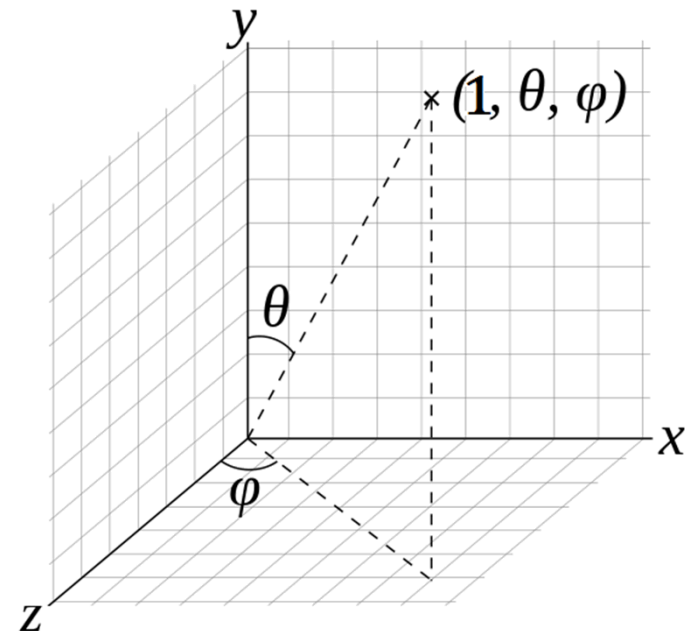
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# Overview

- Development of a new description for solar incident angle
- Test and analysis procedures for mapping solar incident angle response
- Results from mapping the incident angle response of an HCPV module
- Benefits of mapping a CPV module or system
- Future work

# The Deficiency of AOI

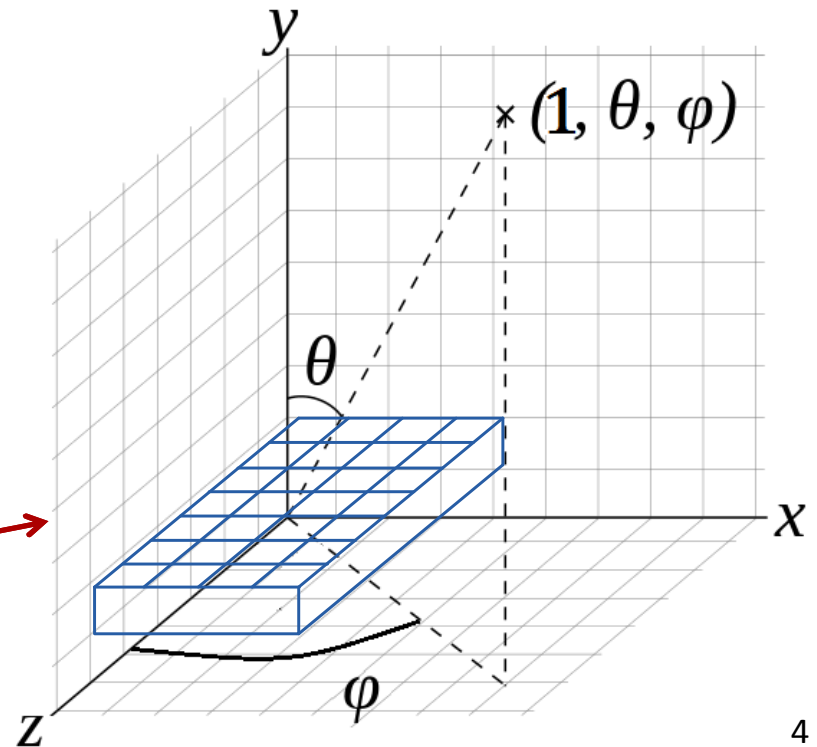
- Angle of incidence (AOI) is the angle between a vector pointing toward the sun and the normal vector of a CPV module or system.
  - It is the “polar angle” of a unit spherical coordinate system ( $\theta$ )
  - There are an infinite number of sun/module orientations with the same AOI
  - If the response of a module to AOI is rotationally asymmetric, it will respond differently to the same AOI depending on how it is rotated



# How to fix the AOI deficiency

- Define the second angle of the unit spherical coordinate system, the “azimuthal angle”, ( $\varphi$ )
  - We call this the “AOI Direction”
- With both angles defined, each module/sun orientation is uniquely identified

In this coordinate system, the module face (or aperture) lies in the x-z plane. The y direction is normal to the module. The vector  $(1, \theta, \varphi)$  points from the module to the sun.



# Benefits of using AOI Direction with AOI

- 100% compatible with the existing definition of AOI alone
  - The addition of AOI Direction does not require a change in the definition of AOI
  - If you don't need AOI Direction (due to rotationally symmetric response), you don't have to specify it
- Provides general nomenclature acceptable to every module
  - Avoids manufacturer or laboratory specific terms such as:
    - “elevation direction” and “cross-elevation direction” – Sandia
    - “parallel incidence” and “perpendicular incidence” – Solaria
    - “aligned AOI” and “transverse AOI” – Solaria working nomenclature
    - “blah1” and “blah2” – SunPower
    - “AOI” and “Receiver Angle” – Cogenra
- Module-relative, not earth-relative, thus it avoids topocentric terms such as “elevation” and “azimuth”
- Provides *unique* coordinates for each sun position relative to the module
  - This allows for the measurement and visualization of the AOI response surface

# Existing methods to measure AOI response

- For modules with rotationally symmetric AOI response, measure the AOI response in one axis
  - How do you know that the AOI response is rotationally symmetric for the entire module or system?
  - Is the test axis representative?
- To address rotationally asymmetric response of a module to AOI, measure the AOI response in two axes
  - Which axes?
  - Why two instead of four (or more)?
  - What's the response if the module is misaligned in *both* axes?

# Mapping AOI response surface (test)

- Mount the device under test (DUT) on a 2-axis tracker
- Move the tracker to orient the module at many AOI/AOI Direction coordinates
  - Measure at many coordinates for a good response curve
  - Keep the test duration short to limit environmental changes
  - Tracker control varies by tracker type (tilt/roll, elevation/azimuth, polar), for elevation/azimuth trackers see D. Riley and C. Hansen, *Sun-Relative Pointing for Dual-Axis Solar Trackers Employing Azimuth and Elevation Rotations*
- Take I-V curve(s) and module temperature(s) at each AOI/AOI Direction coordinate
  - Test during clear-sky conditions with minimal irradiance or spectral changes
  - Simultaneous DNI measurements on a different tracker

# Mapping AOI response surface (analysis)

- Adjust the parameter of interest (e.g.  $I_{MP}$  or  $P_{MP}$ ) to a common operating condition, for example, this might be used for HCPV

$$I_{MP,adj} = I_{MP} \times \frac{E_0}{E} \times [1 + \alpha_{Imp} \times (T_C - T_{C,0})]$$

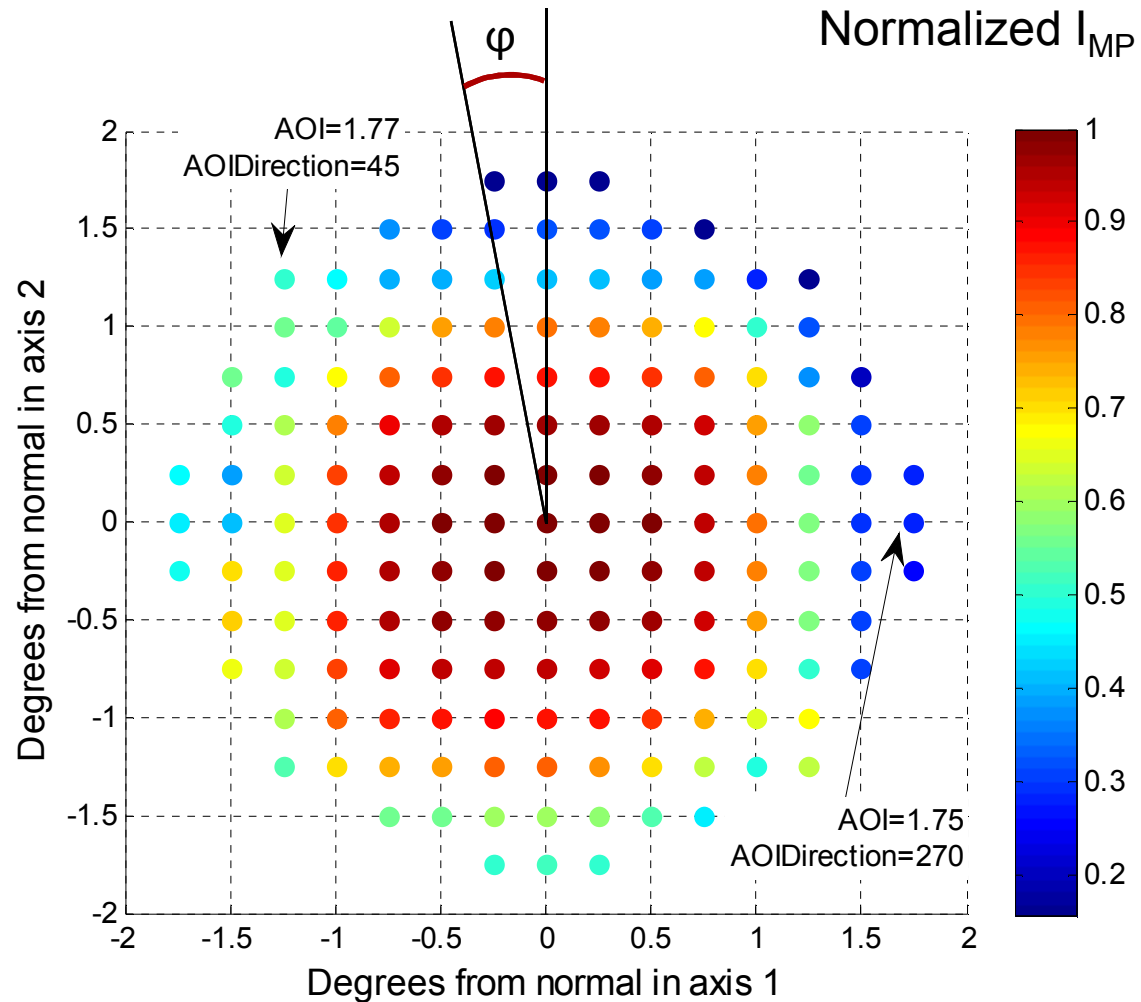
- The adjustment equation may necessarily change for differing parameters of interest or differing types of CPV modules (LCPV or HCPV)
- Normalize the adjusted parameters by dividing by the maximum observed value

$$I_{MP,norm} = \frac{I_{MP,adj}}{\max(I_{MP,adj})}$$

- Plot the normalized parameters as a function of AOI and AOI Direction and visualize the resulting surface

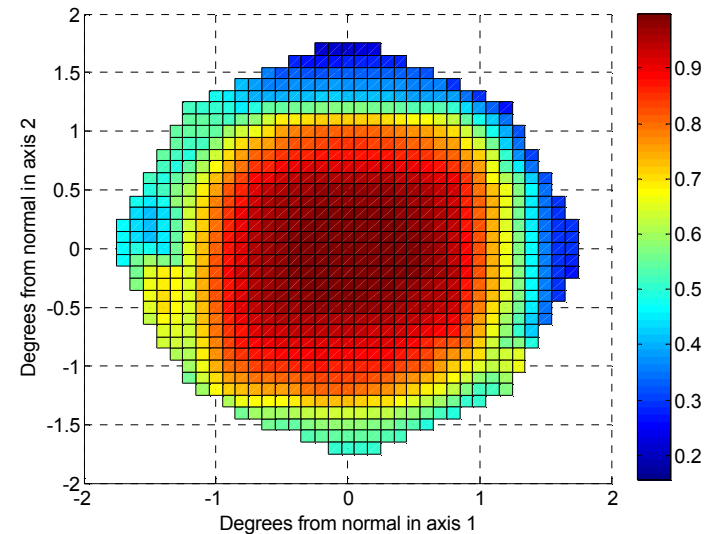
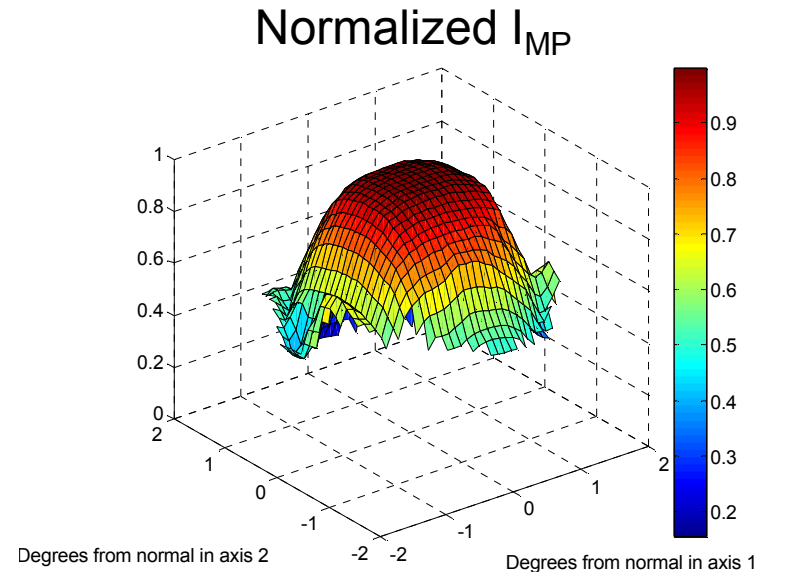
# Results: points

- 161 AOI/AOI Direction coordinates and plotted normalized  $I_{MP}$  values
- AOI ranges from 0 to 1.77
- AOI Direction ranges from 0 to 352
- Each normalized  $I_{MP}$  is a reference point on the response surface



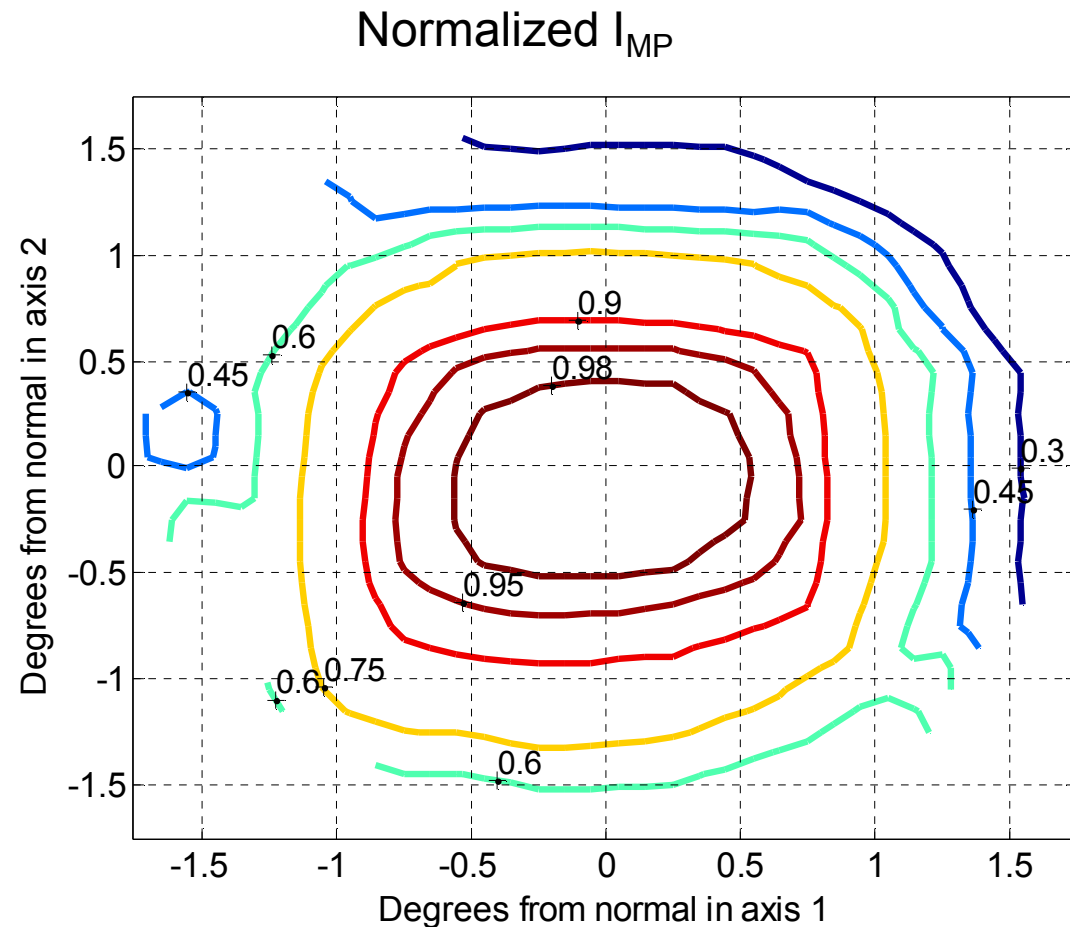
# Results: interpolated surfaces

- Interpolate between the points for a complete response surface
  - Linear interpolation seems to work well for most modules, although other interpolations are possible (e.g. cubic)
- The interpolated surface is interesting to look at, but may not be a good tool to extract useful information



# Results: contour plot

- A contour plot really brings out the shape of the response surface
- Notice the slightly rectangular shape of the isolines
  - Due to optics?
- Easy to determine:
  - The acceptance angle (10% loss)
    - $\pm 0.9$  degrees in AOI Direction 90 and 270
    - $\pm 0.8$  degrees in AOI Direction 0 and 180
    - $\pm 1.0$  degrees in AOI Direction 135 and 315
  - If the module is well oriented on the tracker



# Expanding beyond modules

- Similar testing and analysis could be performed on full systems of HCPV modules on a single tracker

# Information provided by AOI response mapping

- Full response surface, not just a “slice” of the surface
  - Get a “slice” in *any* direction
- Acceptance angle in any direction, even if the response is not symmetric
- Diagnostic information
  - Misaligned optics in a module
  - Misaligned modules on a tracker
  - Any optical defects in the lens(es)

# Past and future work

- AOI and AOI Direction description and tracker movement algorithm
  - Riley and Hansen, “*Sun-Relative Pointing for Dual-Axis Solar Trackers Employing Azimuth and Elevation Rotations*”, DOI: 10.1115/1.4029379
- Adapt the technique to characterize LCPV modules
  - Analysis modification required to remove effects of diffuse radiation utilization in LCPV modules such that only beam response is measured
  - More flexible trackers may be required for larger AOI requirements

# Questions?

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